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Data Sheet No. PD-9.414B

T-39-11

INTERNATIONAL RECTIFIER

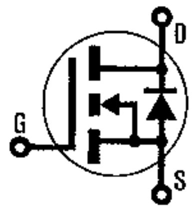
INTERNATIONAL RECTIFIER IOR

HEXFET® TRANSISTORS

IRFZ30

IRFZ32

N-Channel 50 VOLT POWER MOSFETs



TO-220

50 Volt, 0.05 Ohm HEXFET TO-220AB Plastic Package

The HEXFET technology has expanded its product base to serve the low voltage, very low $R_{DS(on)}$ MOSFET transistor requirements. International Rectifier's highly efficient geometry and unique processing of the HEXFET have been combined to create the lowest on resistance per device performance. In addition to this feature all HEXFETs have documented reliability and parts per million quality!

The HEXFET transistors also offer all of the well established advantages of MOSFETs such as voltage control, very fast switching, ease of paralleling, and temperature stability of the electrical parameters.

They are well suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits, and in systems that are operated from low voltage batteries, such as automotive, portable equipment, etc.

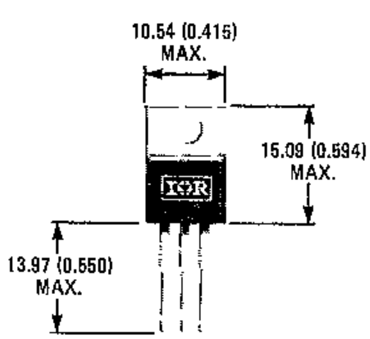
Product Summary

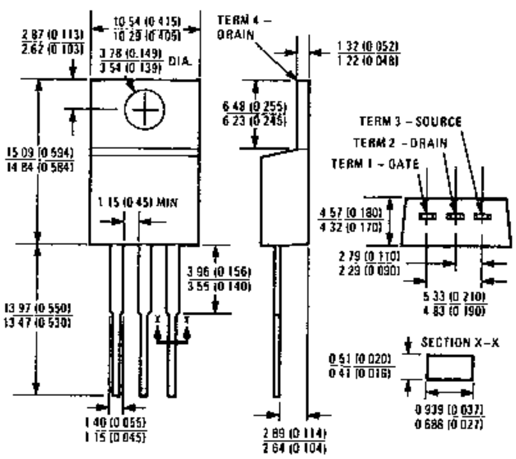
Part Number	V_{DS}	$R_{DS(on)}$	I_D
IRFZ30	50V	0.05Ω	30A
IRFZ32	50V	0.07Ω	25A

Features:

- Extremely Low $R_{DS(on)}$
- Compact Plastic Package
- Fast Switching
- Low Drive Current
- Ease of Paralleling
- Excellent Temperature Stability
- Parts Per Million Quality

CASE STYLE AND DIMENSIONS





Case Style TO-220AB
Dimensions in Millimeters and (Inches)

IRFZ30, IRFZ32 Devices

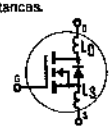
Absolute Maximum Ratings

	Parameter	IRFZ30	IRFZ32	Units
V_{DS}	Drain - Source Voltage ①	50	50	V
V_{DGR}	Drain - Gate Voltage (R_{GS} = 20 KΩ) ①	50	50	V
I_D @ T_C = 25°C	Continuous Drain Current	30	25	A
I_D @ T_C = 100°C	Continuous Drain Current	19	16	A
I_{DM}	Pulsed Drain Current ③	60	60	A
V_{GS}	Gate - Source Voltage	±20		V
P_D @ T_C = 25°C	Max. Power Dissipation	75 (See Fig. 14)		W
	Linear Derating Factor	0.6 (See Fig. 14)		W/K ④
I_{LM}	Inductive Current, Clamped	(See Fig. 15 and 16) L = 100μH 60	60	A
T_J T_{stg}	Operating Junction and Storage Temperature Range	−55 to 150		°C
	Lead Temperature	300 (0.063 in. (1.6mm) from case for 10s)		°C

Electrical Characteristics @ T_C = 25°C (Unless Otherwise Specified)

	Parameter	Type	Min.	Typ.	Max.	Units	Test Conditions
BV_{DSS}	Drain - Source Breakdown Voltage	IRFZ30	50	–	–	V	V_{GS} = 0V
		IRFZ32	50	–	–	V	I_D = 250 μA
$V_{GS(th)}$	Gate Threshold Voltage	ALL	2.0	–	4.0	V	V_{DS} = V_{GS}, I_D = 250 μA
I_{GSS}	Gate-Source Leakage Forward	ALL	–	–	500	nA	V_{GS} = 20V
I_{GSS}	Gate-Source Leakage Reverse	ALL	–	–	−500	nA	V_{GS} = −20V
I_{DSS}	Zero Gate Voltage Drain Current	ALL	–	–	250	μA	V_{DS} = Max. Rating, V_{GS} = 0V
			–	–	1000	μA	V_{DS} = Max. Rating × 0.8, V_{GS} = 0V, T_C = 125°C
$I_{D(on)}$	On-State Drain Current ②	IRFZ30	30	–	–	A	V_{DS} > $I_{D(on)}$ × $R_{DS(on)max.}$, V_{GS} = 10V
		IRFZ32	25	–	–	A	
$R_{DS(on)}$	Static Drain-Source On-State Resistance ②	IRFZ30	–	0.045	0.050	Ω	V_{GS} = 10V, I_D = 16A
		IRFZ32	–	0.065	0.070	Ω	
g_{fs}	Forward Transconductance ②	ALL	9.0	12	–	S(℧)	V_{DS} > $I_{D(on)}$ × $R_{DS(on)}$ max., I_D = 16A
C_{iss}	Input Capacitance	ALL	–	1250	1600	pF	V_{GS} = 0V, V_{DS} = 25V, f = 1.0 MHz
C_{oss}	Output Capacitance	ALL	–	550	800	pF	See Fig. 10
C_{rss}	Reverse Transfer Capacitance	ALL	–	130	200	pF	
$t_{d(on)}$	Turn-On Delay Time	ALL	–	12	25	ns	V_{DD} ≈ 25V, I_D = 16A, Z_o = 50Ω
t_r	Rise Time	ALL	–	16	35	ns	See Fig. 17
$t_{d(off)}$	Turn-Off Delay Time	ALL	–	23	45	ns	(MOSFET switching times are essentially independent of
t_f	Fall Time	ALL	–	16	35	ns	operating temperature.)
Q_g	Total Gate Charge (Gate-Source Plus Gate-Drain)	ALL	–	28	30	nC	V_{GS} = 10V, I_D = 38A, V_{DS} = 0.8 Max. Rating. See Fig. 18 for test circuit. (Gate charge is essentially independent of operating temperature.)
Q_{gs}	Gate-Source Charge	ALL	–	14	–	nC	
Q_{gd}	Gate-Drain ("Miller") Charge	ALL	–	12	–	nC	
L_D	Internal Drain Inductance	ALL	–	3.5	–	nH	Measured from the contact screw on tab to center of die.
			–	4.5	–	nH	Measured from the drain lead, 6mm (0.25 in.) from package to center of die.
L_S	Internal Source Inductance	ALL	–	7.5	–	nH	Measured from the source lead, 6mm (0.25 in.) from package to source bonding pad.

Modified MOSFET symbol showing the internal device inductances.



Thermal Resistance

R_{thJC}	Junction-to-Case	ALL	–	–	1.67	K/W⑤	
R_{thCS}	Case-to-Sink	ALL	–	1.0	–	K/W⑤	Mounting surface flat, smooth, and greased
R_{thJA}	Junction-to-Ambient	ALL	–	–	80	K/W⑤	Typical socket mount

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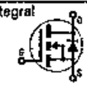
Source-Drain Diode Ratings and Characteristics

I_S	Continuous Source Current (Body Diode)	IRFZ30	—	—	30	A	Modified MOSFET symbol showing the integral reverse P-N junction rectifier. 
		IRFZ32	—	—	25	A	
I_{SM}	Pulse Source Current (Body Diode) ③	IRFZ30	—	—	80	A	
		IRFZ32	—	—	60	A	
V_{SD}	Diode Forward Voltage ②	IRFZ30	—	—	1.6	V	$T_C = 25°C$, $I_S = 30A$, $V_{GS} = 0V$
		IRFZ32	—	—	1.5	V	$T_C = 25°C$, $I_S = 25A$, $V_{GS} = 0V$
t_{rr}	Reverse Recovery Time	ALL	—	160	—	ns	$T_J = 150°C$, $I_F = 30A$, $dI_F/dt = 100A/\mu s$
Q_{RR}	Reverse Recovered Charge	ALL	—	1.5	—	μC	$T_J = 150°C$, $I_F = 30A$, $dI_F/dt = 100A/\mu s$
t_{on}	Forward Turn-on Time	ALL	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $L_S + L_D$.				

① $T_J = 25°C$ to $150°C$. ② Pulse Test: Pulse width ⩽ 300μs, Duty Cycle ⩽ 2%. ③ Repetitive Rating: Pulse width limited by max. junction temperature. See Transient Thermal Impedance Curve (Fig. 5).

④ K/W = °C/W
W/K = W/°C

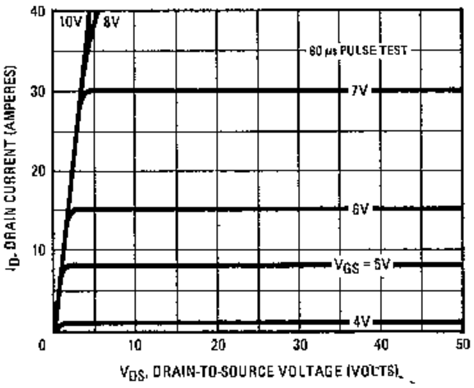


Fig. 1 — Typical Output Characteristics

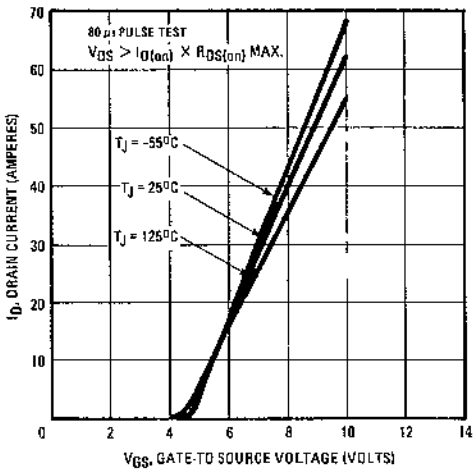


Fig. 2 — Typical Transfer Characteristics

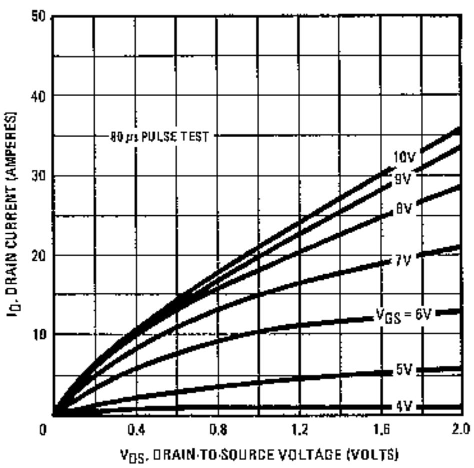


Fig. 3 — Typical Saturation Characteristics

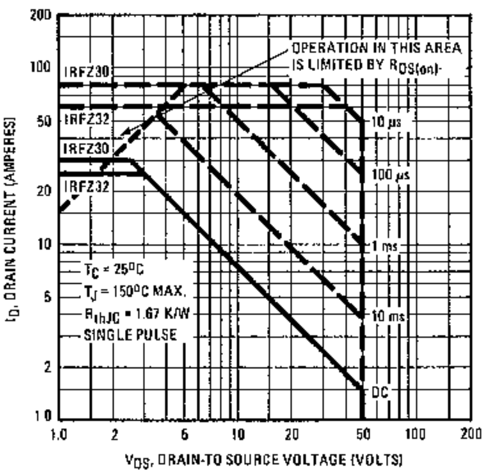


Fig. 4 — Maximum Safe Operating Area

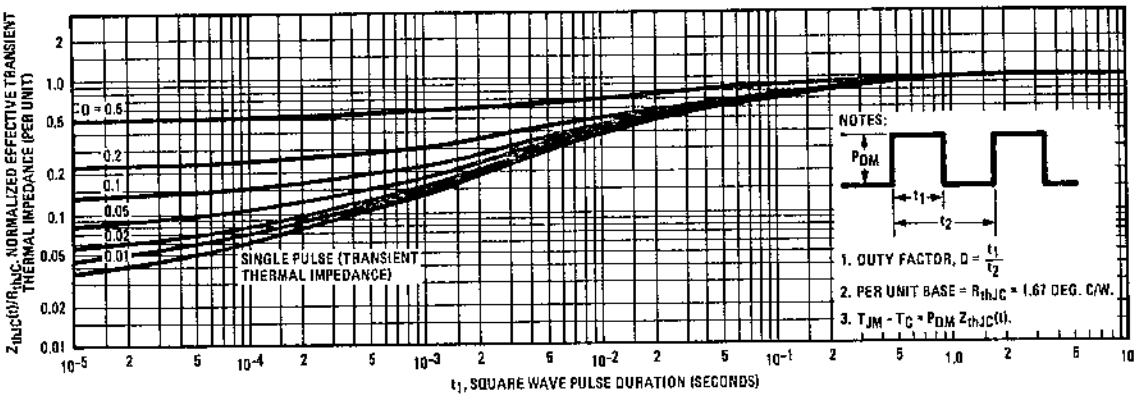


Fig. 5 – Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

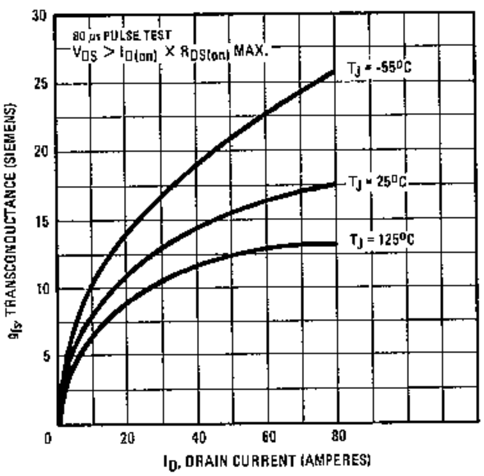


Fig. 6 Typical Transconductance Vs. Drain Current

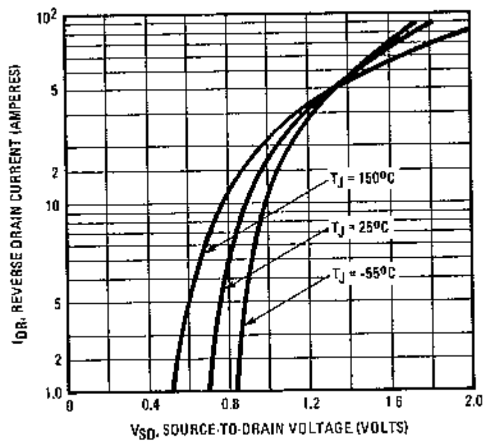


Fig. 7 – Typical Source-Drain Diode Forward Voltage

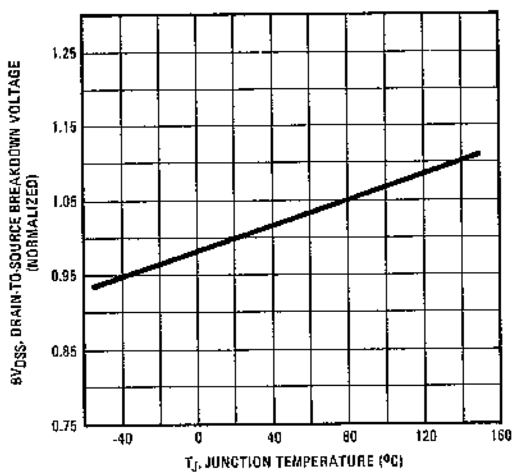


Fig. 8 – Breakdown Voltage Vs. Temperature

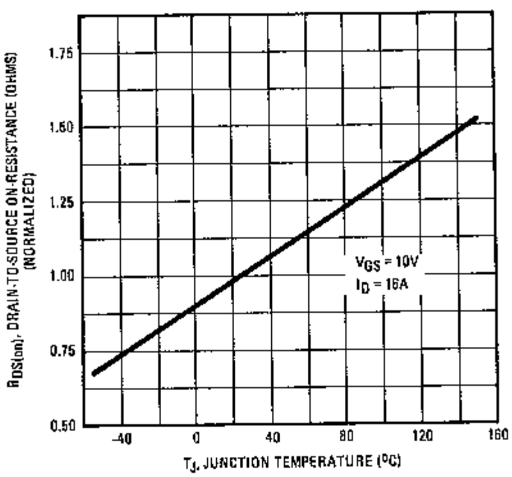


Fig. 9 – Normalized On-Resistance Vs. Temperature

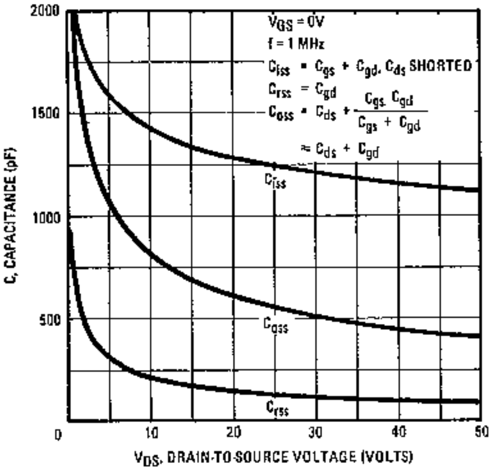


Fig. 10 – Typical Capacitance Vs. Drain-to-Source Voltage

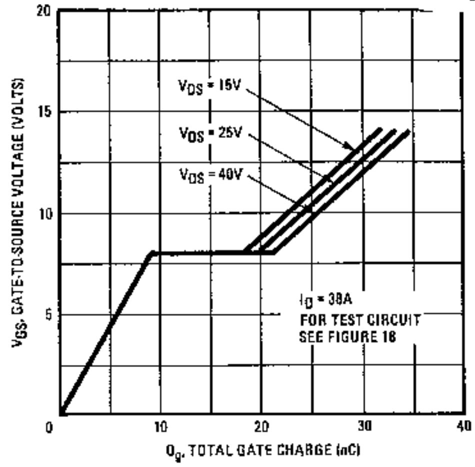


Fig. 11 – Typical Gate Charge Vs. Gate-to-Source Voltage

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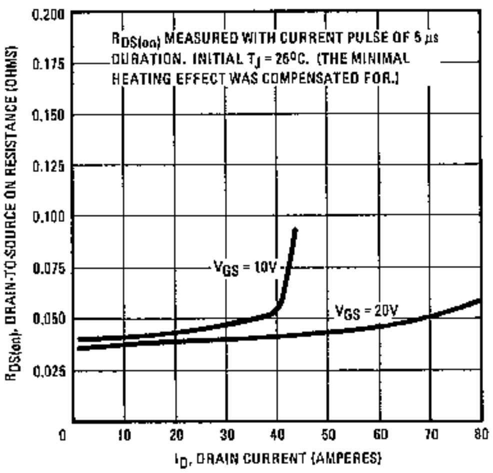

Fig. 12 – Typical On-Resistance Vs. Drain Current

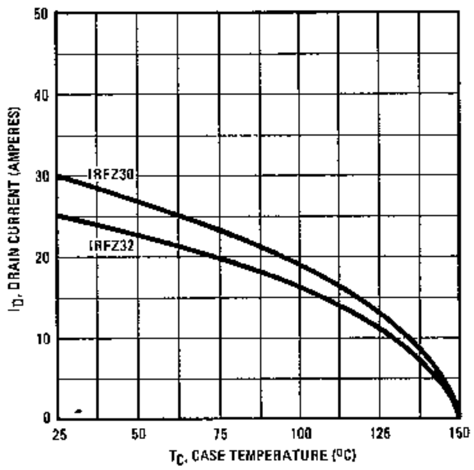

Fig. 13 – Maximum Drain Current Vs. Case Temperature

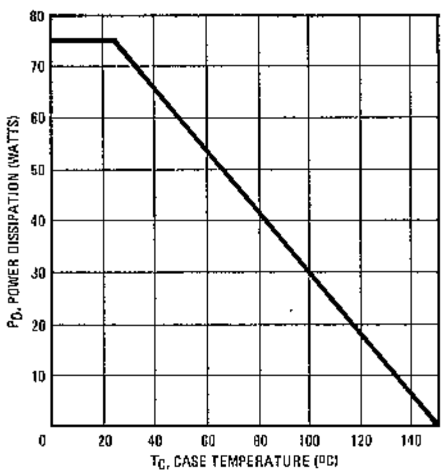

Fig. 14 — Power Vs. Temperature Derating Curve

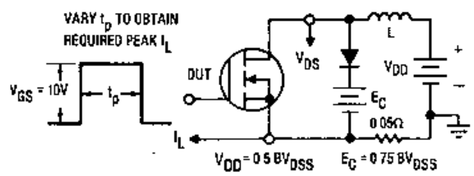

Fig. 15 — Clamped Inductive Test Circuit

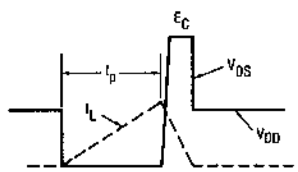

Fig. 16 — Clamped Inductive Waveforms

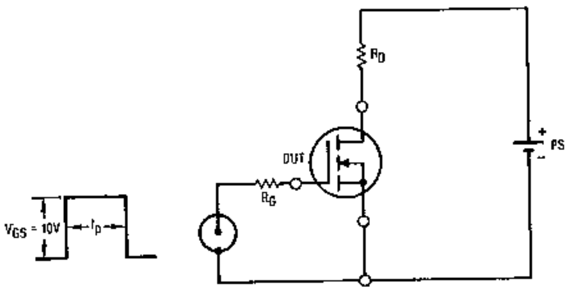

Fig. 17 — Switching Time Test Circuit

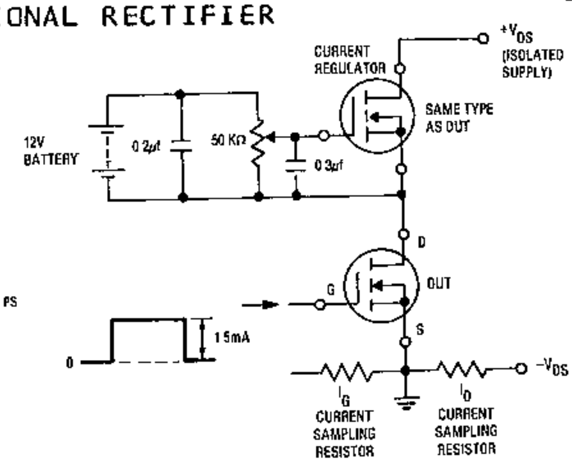

Fig. 18 — Gate Charge Test Circuit

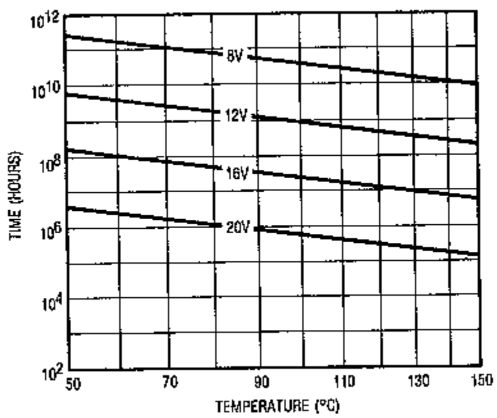

*Fig. 19 — Typical Time to Accumulated 1% Failure

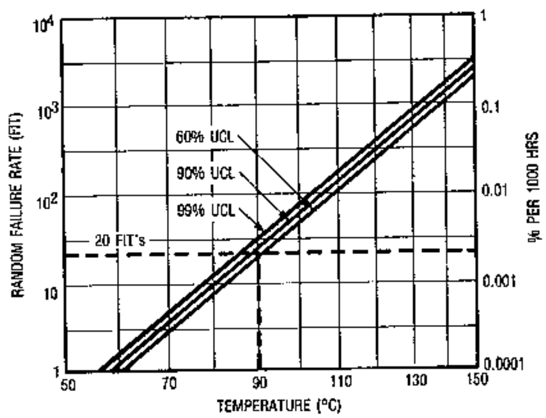

*Fig. 20 — Typical High Temperature Reverse Bias (HTRB) Failure Rate

*The data shown is correct as of April 15, 1987. This information is updated on a quarterly basis; for the latest reliability data, please contact your local IR field office.